

PowerMOS transistor

Isolated version of BUK455-200A/B

BUK475-200A/B

GENERAL DESCRIPTION

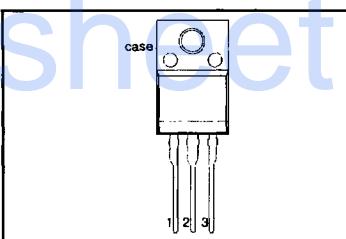
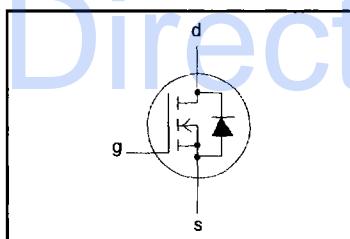
N-channel enhancement mode field-effect power transistor in a plastic full-pack envelope. The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	BUK475	MAX. -200A	MAX. -200B	UNIT
V_{DS}	Drain-source voltage		200	200	V
I_D	Drain current (DC)		7.6	7	A
P_{tot}	Total power dissipation		30	30	W
T_J	Junction temperature		150	150	°C
$R_{DS(ON)}$	Drain-source on-state resistance		0.23	0.28	Ω

PINNING - SOT186A

PIN	DESCRIPTION
1	gate
2	drain
3	source
case	isolated

PIN CONFIGURATION**SYMBOL****LIMITING VALUES**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MAX.		UNIT
			MIN.	MAX.	
V_{DS}	Drain-source voltage	-		200	V
	Drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	200	V
	Gate-source voltage	-	-	30	V
I_D	Drain current (DC)	$T_{hs} = 25^\circ\text{C}$	-	7.6	A
	Drain current (DC)	$T_{hs} = 100^\circ\text{C}$	-	4.8	A
	Drain current (pulse peak value)	$T_{hs} = 25^\circ\text{C}$	-	30	A
P_{tot}	Total power dissipation	$T_{hs} = 25^\circ\text{C}$	-	30	W
	Storage temperature	-	-55	150	°C
	Junction temperature	-	-	150	°C

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th(j-hs)}$	Thermal resistance junction to heatsink	with heatsink compound	-	-	4.17	K/W
$R_{th(j-a)}$	Thermal resistance junction to ambient		-	55	-	K/W

PowerMOS transistor

BUK475-200A/B

STATIC CHARACTERISTICS $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	200	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V
I_{DSS}	Zero gate voltage drain current	$V_{DS} = 200 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$	-	1	10	μA
I_{DS}	Zero gate voltage drain current	$V_{DS} = 200 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125^\circ\text{C}$	-	0.1	1.0	mA
I_{GSS}	Gate source leakage current	$V_{GS} = \pm 30 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nA
$R_{DS(ON)}$	Drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 7 \text{ A}$	BUK475-200A	-	0.2	0.23 Ω
			BUK475-200B	-	0.22	0.28 Ω

DYNAMIC CHARACTERISTICS $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g_f	Forward transconductance	$V_{DS} = 25 \text{ V}; I_D = 7 \text{ A}$	6	8.4	-	S
C_{iss}	Input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	1400	1750	pF
C_{oss}	Output capacitance		-	190	250	pF
C_{rss}	Feedback capacitance		-	55	80	pF
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 30 \text{ V}; I_D = 3 \text{ A}; V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega; R_{gen} = 50 \Omega$	-	18	30	ns
t_r	Turn-on rise time		-	35	60	ns
$t_{d(off)}$	Turn-off delay time		-	85	120	ns
t_f	Turn-off fall time		-	35	50	ns
L_d	Internal drain inductance	Measured from drain lead 6 mm from package to centre of die	-	4.5	-	nH
L_s	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	7.5	-	nH

ISOLATION LIMITING VALUE & CHARACTERISTIC $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{isol}	R.M.S. isolation voltage from all three terminals to external heatsink	$f = 50-60 \text{ Hz}$; sinusoidal waveform; R.H. $\leq 65\%$; clean and dustfree	-		2500	V
C_{isol}	Capacitance from T2 to external heatsink	$f = 1 \text{ MHz}$	-	10	-	pF

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{DR}	Continuous reverse drain current	-	-	-	7.6	A
I_{DRM}	Pulsed reverse drain current	-	-	-	30	A
V_{SD}	Diode forward voltage	$I_F = 7.6 \text{ A}; V_{GS} = 0 \text{ V}$	-	1.0	1.5	V
t_{rr}	Reverse recovery time	$I_F = 7.6 \text{ A}; -dI_F/dt = 100 \text{ A}/\mu\text{s}$	-	150	-	ns
Q_{rr}	Reverse recovery charge	$V_{GS} = 0 \text{ V}; V_R = 30 \text{ V}$	-	1.3	-	μC

PowerMOS transistor

BUK475-200A/B

AVALANCHE LIMITING VALUE $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
W_{DSS}	Drain-source non-repetitive unclamped inductive turn-off energy	$I_D = 14 \text{ A}$; $V_{DD} \leq 100 \text{ V}$; $V_{GS} = 10 \text{ V}$; $R_{GS} = 50 \Omega$	-	-	100	mJ

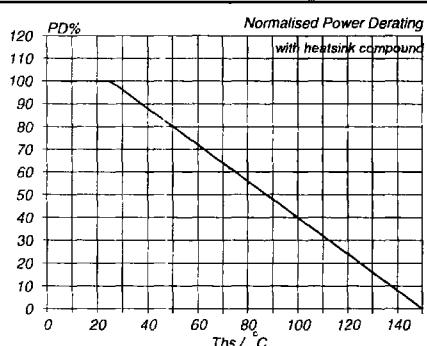


Fig. 1. Normalised power dissipation.
 $PD\% = 100 P_D / P_{D, 25^\circ\text{C}} = f(T_{hs})$

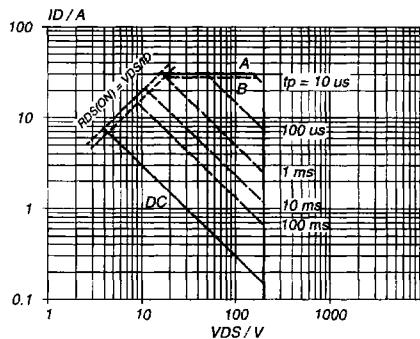


Fig. 3. Safe operating area. $T_{hs} = 25^\circ\text{C}$
 I_D & I_{DM} = $f(V_{DS})$; I_{DM} single pulse; parameter t_p

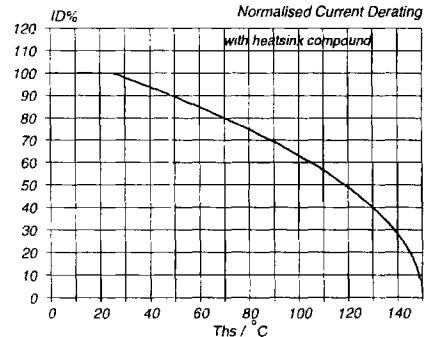


Fig. 2. Normalised continuous drain current.
 $ID\% = 100 I_D / I_{D, 25^\circ\text{C}} = f(T_{hs})$; conditions: $V_{GS} \geq 10 \text{ V}$

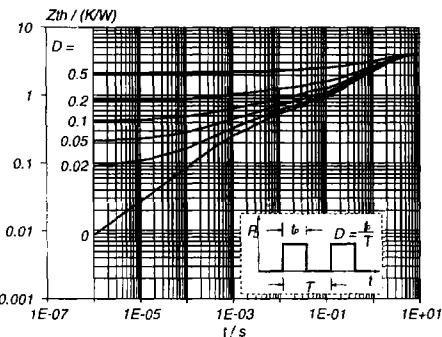


Fig. 4. Transient thermal impedance.
 $Z_{th, T} = f(t)$; parameter $D = t_p/T$

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BUK475-200A/B

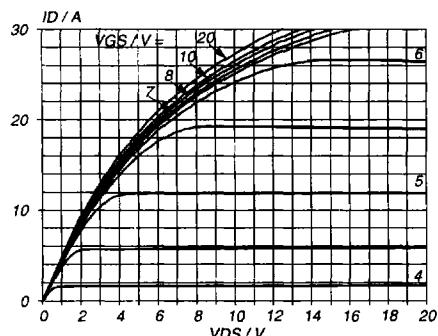


Fig.5. Typical output characteristics, $T_j = 25^\circ\text{C}$.
 $I_D = f(V_{DS})$; parameter V_{GS}

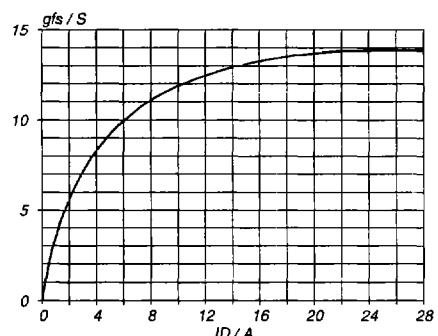


Fig.8. Typical transconductance, $T_j = 25^\circ\text{C}$.
 $g_{fs} = f(I_D)$; conditions: $V_{DS} = 25\text{ V}$

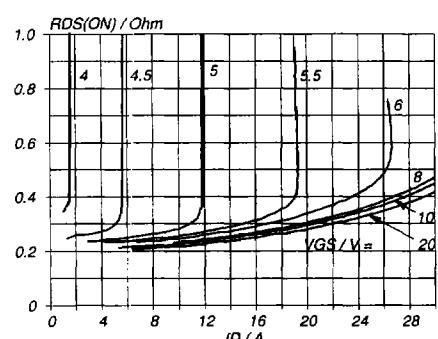


Fig.6. Typical on-state resistance, $T_j = 25^\circ\text{C}$.
 $R_{DS(ON)} = f(I_D)$; parameter V_{GS}

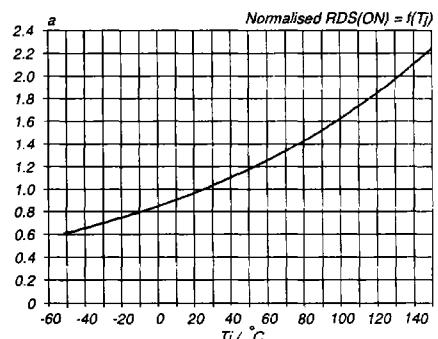


Fig.9. Normalised drain-source on-state resistance.
 $a = R_{DS(ON)}/R_{DS(ON)25^\circ\text{C}} = f(T_j)$; $I_D = 7\text{ A}$; $V_{GS} = 10\text{ V}$

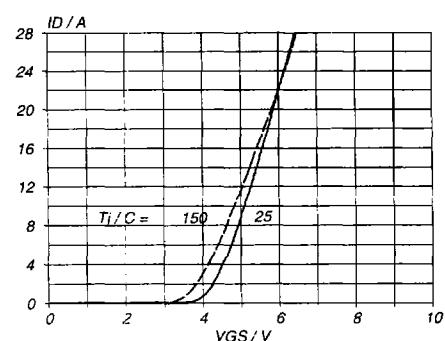


Fig.7. Typical transfer characteristics.
 $I_D = f(V_{GS})$; conditions: $V_{DS} = 25\text{ V}$; parameter T_j

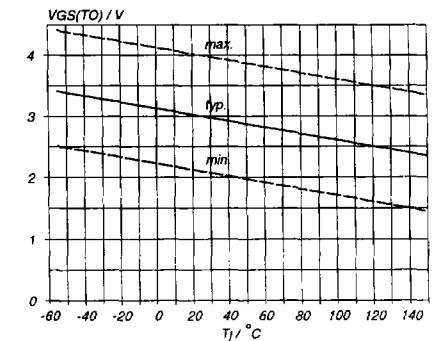


Fig.10. Gate threshold voltage.
 $V_{GS(TO)} = f(T_j)$; conditions: $I_D = 1\text{ mA}$; $V_{DS} = V_{GS}$

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